



## **Simulation of THz Spectra**

*Bolko Beutner*, DESY XFEL Beam Dynamics Meeting 28.04.2008



# Introduction



- THz spectra and their dependence on ACC1 phase were measured
- Strong changes of power for less than a degree phase change
- Patterns in the spectra for high off crest phases
- Structures in the range of a few ten micron





# Introduction



- To understand the features of the spectra start-to-end simulations (thanks to M. Dohlus) for FLASH are used
- Spectra are generated from the longitudinal charge profiles for different ACC1 phases
- THz spectrometer response is generated from these spectra







• From the Fourier transform of the longitudinal charge profile one calculates the Form factor, the wavelength spectrum, and the spectrometer



XFEL Beam Dynamics Meeting 28.04.2008

Bolko Beutner, DESY



Bolko Beutner, DESY





- Steep changes of spectra with ACC1 phase (only 1 deg steps in simulations)
- Substructure for off crest phases higher than about 10 deg
- Noise below about 20 micron



#### Comparison with measurements GEMEINSCHAFT

HELMHOLTZ



- Phase shift between simulations and measurements of about 2deg or additional features at ~7deg in measurements
- simulations were not set up to match measurements (ACC1 gradient and BC bending angles might be slightly different)







- Double spike structures after about 9 deg off crest
- Double Gaussian is fitted to charge profile and used for spectra generation





• Double Gaussian is not the best choice at 10 deg



- Agreement of coarse structure between double **Gaussian and Simulations**
- For Phases higher than 12 deg the spike in the spectrum is reduced for real data (effects of third spike?)

Π

400

Wavelength [µm]

200

600

800

1000

600

600

800

1000

n

200

400

Wavelength [µm]

800

1000

FLASH



- Spike separation is compared with the wavelength spectrum
- Some correlations are visible







- Simple structures build from Gaussians are used for qualitative understanding
- Small scale modulations lead to a sharp signal at the wavelength
- Two Gaussians gives rise to substructure in the spectrum

x 10<sup>-24</sup> 1.5 З Intensity [a.u.] carge [a.u.] 0.5 0 £ 20 0.5 30 Γn 10 n. time [ps] Frequency [THz] x 10<sup>-24</sup> x 10<sup>-31</sup> IFI<sup>2</sup>  $1/\lambda^2 |F|^2$ 8 Intensity [a.u.] ntensity [a.u.] 6 0.5 Ο £ 2000 3000 3000 īΠ. 1000 4000 2000 4000 Ο 1000 Wavelength [µm] Wavelength [µm]

> Gaussian (sigma = 0.5ps) Gaussian with sine (lambda = 1ps/300um) two half Gaussians (Delta s = 8ps)







• Minima are caused by destructive interference between the radiation of the two spikes



XFEL Beam Dynamics Meeting 28.04.2008

Bolko Beutner, DESY





• Spike separation from the double Gaussian fit is used to estimate minima position



XFEL Beam Dynamics Meeting 28.04.2008

Bolko Beutner, DESY





- For ACC1 phase offsets higher than ~8deg minima patterns ulletexist in measured spectra => indications for double spike structure
- Qualitative correspondence to estimated pattern

ELMHOLTZ



• Minima structure in the phase range from 9 to 10 deg are determined and used for a estimation of spike separation  $\Delta t$  using a linear fit to  $\lambda_n = \frac{\Delta t c}{n-1/2}$ 



Substructure in measurements II

HELMHOLTZ





# Substructure in measurements



• Minima structure in the phase range from 9 to 10 deg are determined and used for a estimation of spike separation  $\Delta t$  using a linear fit to  $\lambda_n = \frac{\Delta t c}{n-1/2}$ 



# **Comparison with Simulations**



- Estimated spike separation from ~150 to ~300 micron
- Simulations go from ~100 to ~150 micron

HELMHOLTZ

GEMEINSCHAFT

 Simulations are not specifically set up to match measurements (RF and BC settings)





# Summary



- Steep increase of THz signal for small phase changes is reproduced in simulations
- Phase shift or additional feature at ~7 deg in measurements
- Qualitative understanding of substructure induced by double spikes
- Estimation of double spike structure from spectra is possible (no detailed error analysis yet)
- Simulations give no reliable information on micro bunching (<20 micron)</li>



### **Next Steps**



- Detailed analysis of measured double spike spectra
- Complete analysis of old and recent measured phase scan data
- more detailed start to end simulations
  - finer phase steps
  - Setup of simulations to match measurements
- Extract spike separation from simulated spectra to crosscheck the analysis procedures
- Comparison with micro bunching simulation models (<20 micron)</li>
- Decomposition of charge profiles in more than two Gaussians (Delsim-Hashemi)